



Attorney's Docket No.: 14850-002001 *jfw*

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Ares Rosakis, et al. Art Unit: 2877
Serial No.: 10/766,302
Filed : January 27, 2004
Title : OPTICAL CHARACTERIZATION OF SURFACES AND PLATES

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicants call attention to the attached Information Disclosure Statement and document listed on form PTO-1449.

This filing is being made before the receipt of a first Office action on the merits. No fee is required.

Consideration of the foregoing and enclosure plus the return of a copy of the enclosed form PTO-1449 with the Examiner's initials in the left column per MPEP 609 are earnestly solicited along with an early action on the merits.

CERTIFICATE OF MAILING BY FIRST CLASS MAIL

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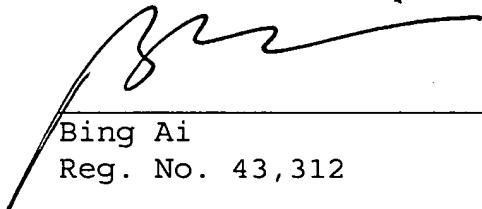

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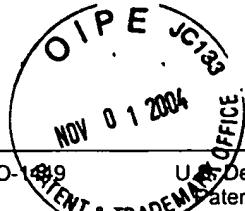
Respectfully submitted,



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Sheet 1 of 1

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 14850-002001	Application No. 10/766,302
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Ares Rosakis, et al.	
		Filing Date January 27, 2004	Group Art Unit 2877

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6031611	2/29/2000	Rosakis, et al.			
	AB	6469788	10/22/2002	Boyd, et al.			
	AC	6513389	2/4/2003	Suresh, et al.			
	AD	6600565	7/29/2003	Suresh, et al.			
	AE	2004/0075825	4/22/2004	Suresh, et al.			
	AF	6781702	8/24/2004	Giannakopoulos, et al.			
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
	AL						
	AM						
	AN						
	AO						
	AP						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	Wikstrom, et al.; Thermoelastic analysis of periodic thin lines deposited on a substrate; 1999; Journal of the Mechanics and Physics of Solids, 47 (1999); pps 1113-1130
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	